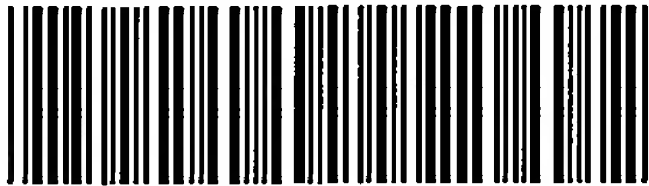


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/661,736	LAI, CHUAN DE	
	Examiner	Art Unit	
	Richard H. Kim	2871	

SEARCHED			
Class	Subclass	Date	Examiner
362	27,31,559, 560,561	5/23/2005	RHK

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
East Search	5/23/2005	RHK